Hybrid 7p126 Traveler

May 31, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 7P126 has die: 239-063 239-067 239-068 239-073 239-074 239-077 239-125

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 7p126 classification info. Created 08:58:46 05/30/00

Hybrid 7p126 quality: fair
Chip classification: fair fair fair fair fair fair fair
Bad channels (chip-channel): 0-57 1-9 1-23 2-11 3-53 6-94
Bad cells: none
Random bad capacitors (chip-cell-channel): 2-12-115 2-13-115 2-14-115
   2-15-115 2-25-115 2-27-115 2-45-115 2-5-115 4-14-72 4-14-73 5-6-7
Channels at pedestal needed for DCMS: 29.6 30.6 29.7 30.7 29.7 29.5 31.6
```

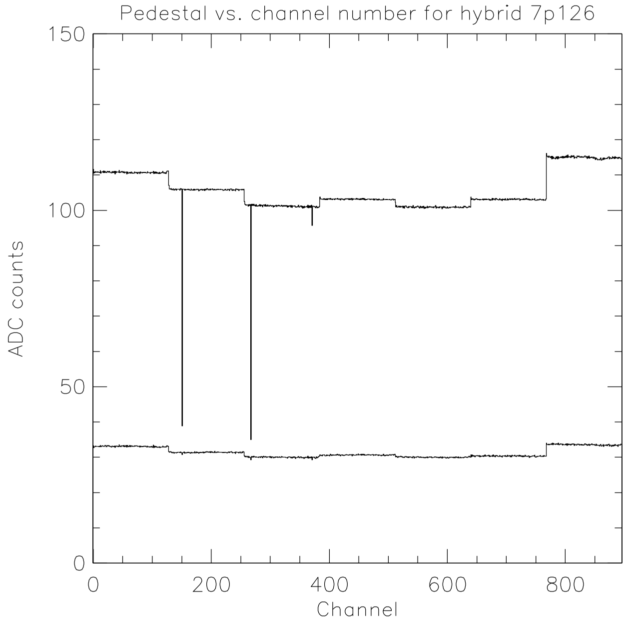
4 Comments

Encapsulated. FE DV finger gold bonds. HV tested.

5 Pedestal

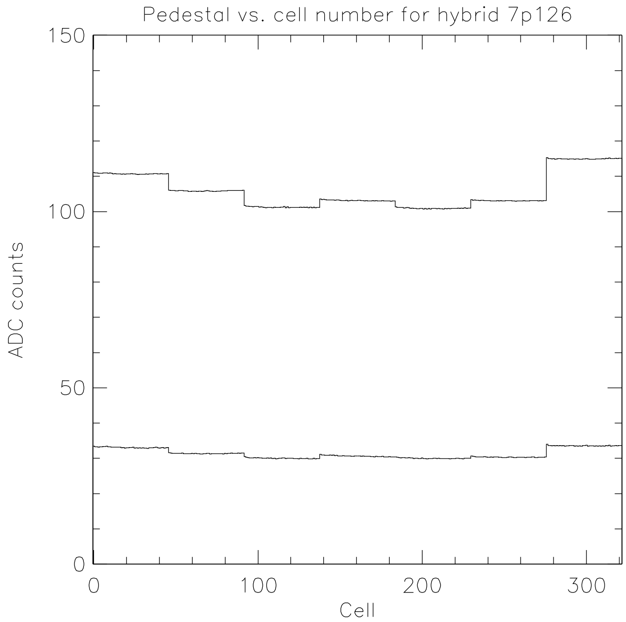
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

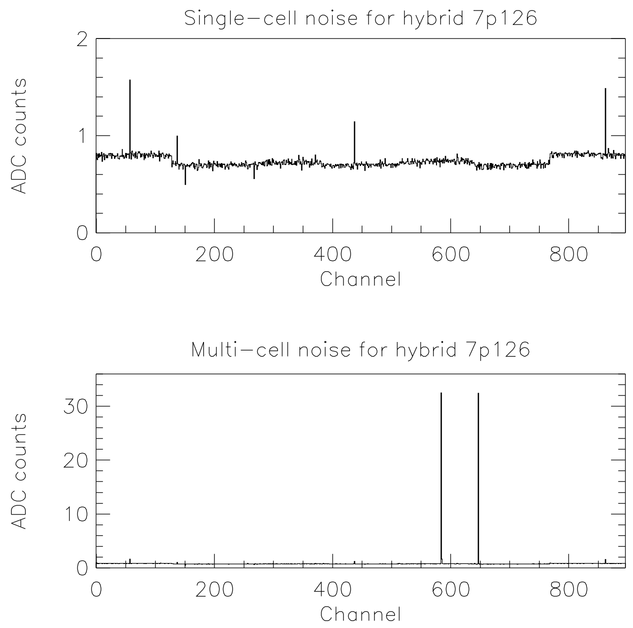
Pedestal vs. Pipeline Cell ID



6 Noise

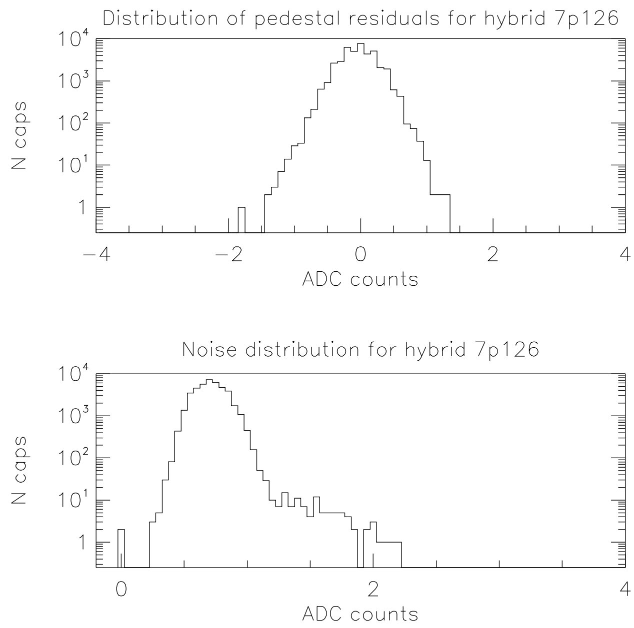
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise



The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in